

# Search Notes



Application/Control No.

10/721,747

Examiner

Dinh Q. Nguyen

Applicant(s)/Patent und r  
Re xamination

HEINRICH ET AL.

Art Unit

3752

## SEARCHED

Class	Subclass	Date	Examiner
239	597		
	594		
	434.5		
	423	1-24-05	WJ
451	102	1-24-05	WJ
118	308	1-24-05	WJ
427	192	1-24-05	WJ

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR